STANDARD DIVISION PRACTICE <u>TWI – Veolia ES Technical Solutions, L.L.C.</u>

TITLE: Varian Inductively Coupled Plasma – Optical	SDP NUMBER: 5318
Emission Spectrometry (ICP-OES)	EFFECTIVE DATE: June 2011
DEPARTMENT: <u>Laboratory</u>	PAGE: of13
SECTION:	ORIGINAL DATE: Nov 2001
REPLACES: Number	Date
APPROVED BY:	, General Manager

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1.0 Purpose:

To establish a written procedure for analysis of trace elements in solution by Inductively Couple Plasma-Optical Emission Spectrometry (ICP-OES) on the Varian 715 Instrument.

2.0 Scope:

This method uses a radial viewing of the plasma and simultaneous optical spectrometry for the determination of the trace elements: Arsenic, Beryllium, Cadmium, Chromium, Lead and screening for Mercury, in acid digested solutions of waste samples. For samples containing high concentrations of mercury, or where a small representative sample cannot be obtained for analysis using the direct mercury analyzer (DMA), the extract may be analyzed for Mercury by ICP.

3.0 Summary of Method:

After microwave digestion and dilution, the extracts are analyzed by ICP. Argon gas is used to introduce the digestate into the nebulizer, where it becomes a fine aerosol mist. The mist is injected up the length of the torch assembly into the plasma. Light emitted from the plasma is focused through an optical lens and passed through an entrance slit into the spectrometer. Each element emits energy at a wavelength proportional to the concentration of that element. The energy intensity at each element's wavelength is measured to provide a quantitative result.

40 Users:

Trained Veolia Sauget Laboratory employees and analysts under supervision.

- 5.0 Personal Protective Equipment:
 - 5.1 Safety Glasses
 - 5.2 Tyvek/Work Uniform
 - 5.3 Latex/Nitrile Gloves
 - 5.4 Exhaust Fan
 - 5.5 Marble Chips
 - 5.6 Fume Hoods
- 6.0 Specialized Equipment, Tools, Supplies:
 - 6.1 Instruments and Equipment
 - 6.1.1 Varian ICP-OES
 - 6.1.2 Lytron Modular Cooling System
 - 6.1.3 Argon gas supply (high purity) and Regulator

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	6.1.4	Compute	er with ICP II Expert Soft	ware						
	6.1.5	Printer	1							
	6.1.6	Type I V	Vater Filtration System							
6.2	Instrumer	nt Expenda	ables (use part # listed or e	equivalent)						
	6.2.1	SeaSpra	y Nebulizer - Varian part	# 20-100964-00						
	6.2.2	Cyclonic	c Spray Chamber – Variar	n part # 791004370	0					
	6.2.3	Radial Q	Quartz Torch – Varian part	t # 2010069690						
	6.2.4	Radial Q	Quartz Torch Bonnet – Var	rian part # 2010070	0790					
	6.2.5	Sipper w	vand kit – ThermoElement	tal part # 13300600)					
	6.2.6	Blue tub	ing with diameter 1.65mn	n – Varian part #3	7-10034	6-00				
	6.2.7	White tu	ibing with diameter 1.02m	nm – Varian part #	37-1003	44-00				
	6.2.8	Tubing for torch								
6.2.9		Transfer	Tubing from Chamber to	Torch						
6.3	Supplies									
	6.3.1	Pipet Fil	ller/Bulb							
	6.3.2	Serologi	cal pipettes, disposable, ra	ange 1 – 10 mL						
	6.3.3		pettor and tips with range							
	6.3.4	Micropi	pettor and tips with range	20-200 ul						
	6.3.5	Micropipettor and tips with range 200-1000 ul								
	6.3.6	1L and 250ml Amber Polypropylene Bottles								
	6.3.7	50ml Ce	entrifuge Tubes, trace meta	als grade						
	6.3.8	Gallon-s	size waste jugs and approp	oriate labels						
	6.3.9	Kimwip	es							
	6.3.10	Repipett	tors 1-10mL							
	6.3.11	Transfer	Pipets							
6.4	Standards	& Reage	nts							
	6.4.1	Deionize	ed (DI) Water, Type 1							
	6.4.2	Concent	rated Nitric Acid (H ₂ NO ₃)), trace metals grad	le					
	6.4.3	Concent	rated Hydrochloric Acid ((HCl), trace metals	grade					
	6.4.4	First Sou	urce Standards							
		6.4.4.1	1,000 μg/ml Arsenic (A	As) Stock Standard						
		6.4.4.2	1,000 μg/ml Beryllium	(Be) Stock Standa	ırd					
		6.4.4.3	1,000 μg/ml Cadmium	* *						
		6.4.4.4	1,000 μg/ml Chromiun	n (Cr) Stock Standa	ard					

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_		
	6.4.4.5	1,000 µg/ml Mercury (Hg) Stock Standard
	6.4.4.6	1,000 µg/ml Lead (Pb) Stock Standard
	6.4.4.7	Stock Mix 1 (µg/ml) – 5,000 As, Cd, Cr, Pb & 2,000 Be
	6.4.4.8	Stock Mix 2 (µg/ml) – 50.0 As, 1.0 Be, 10.0 Cd, 25.0 Cr, Pb
	6.4.4.9	High Calibration/Calibration Curve Verification Standard (μg/ml – 5.0 As, Cd, Cr, Pb & 2.0 Be, Hg
	6.4.4.10	Mid-Level Calibration/Calibration Curve Verification Standard (CCV) (μg/ml) – 2.5 As, Cd, Cr, Pb & 1.0 Be, Hg
	6.4.4.11	Low-Level Calibration/Calibration Curve Verification Standard (LLCCV) (μg/ml) – 0.05 As, 0.001 Be, 0.01 Cd, 0.025 Cr, Pb & 0.02 Hg
6.4.5	Second S	ource Standards (must be purchased from different vendor than 1st
	source)	` •
	6.4.5.1	1,000 μg/ml Arsenic (As) Stock Standard
	6.4.5.2	1,000 µg/ml Beryllium (Be) Stock Standard
	6.4.5.3	1,000 µg/ml Cadmium (Cd) Stock Standard
	6.4.5.4	1,000 μg/ml Chromium (Cr) Stock Standard
	6.4.5.5	1,000 µg/ml Mercury (Hg) Stock Standard
	6.4.5.6	1,000 µg/ml Lead (Pb) Stock Standard
	6.4.5.7	Initial Calibration Verification (ICV) Stock Mix (μg/ml) – 250 A Cd, Cr, Pb & 100 Be, Hg
	6.4.5.8	ICV (μ g/ml) – 2.5 As, Cd, Cr, Pb & 1.0 Be, Hg
	6.4.5.9	Laboratory Control Sample (LCS) – Standard Reference Material (digested)
	6.4.5.10	Spike Solution (μg/ml) – 100 As, Be, Cd, Cr, Pb, Hg (added prior to microwave digestion)
6.4.6		uning Solution (5,000mg/ml K & 50.0mg/ml Al, As, Ba, Cd, Cr, Co In, Mo, Ni, Se, Sr, Zn) diluted 1/10.
6.4.7	For the st	andards' preparation procedures refer to SDP 5300 "Standards and Preparation".
648	_	an T for Chiller Conditioning

7.0 Interferences:

7.1 Physical interferences are effects associated with the sample nebulization and transport processes. Changes in viscosity and surface tension can cause significant inaccuracies, especially in samples containing high dissolved solids or high acid concentrations. This is reduced by diluting the sample and using a peristaltic pump.

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- 7.2 Chemical interferences include molecular compound formation, ionization effects and solute vaporization effects. This can be minimized by a careful selection of operating conditions (power, torch position, etc.) and by matrix matching.
- 7.3 Memory interferences result when analytes in a previous sample contribute to the signals measured in a new sample. This can be the result of sample deposition on the uptake tubing and from a build up on the spray chamber or torch. Memory interferences can be reduced or eliminated by flushing the system with a rinse blank in between samples and by making sure that all parts of the instrument are meticulously clean prior to use.
- 7.4 Spectral Interferences result when high concentrations of a metal exist in a sample and their wavelength overlaps another element's wavelength. These can be eliminated by a program in the software called FACT. This has already been performed for beryllium to subtract out hydroxide peaks and for lead to subtract out the high background noise. See the manual provided with the instrument in order to run FACT. For normal samples, interferences can usually be seen on the graph results after a sample run. If the analyst suspects a spectral interference, they should see the QA/QC chemist on how to proceed.

8.0 Procedures:

The ICP-OES analysis technique demands a particularly high standard of care in all activities that affect the accuracy and precision of the analytical result. Scrupulous cleanliness is essential in all laboratory procedures. Standards and samples must be meticulously prepared and carefully handled. Strict precautions must be taken to avoid contamination of the instrument and samples. All laboratory apparatuses should be thoroughly clean before and after use.

- 8.1 Start-up the Instrument
 - 8.1.1 Turn on Exhaust fan (switch is located behind the Thermo ICP)

CAUTION: Exhaust fan must always be turned on before operating the ICP or serious damage to the instrument can occur.

- 8.1.2 Turn on Lytron Modular Cooling System (MCS) by flipping the switch on the back, directly above it's electrical plug.
- 8.1.3 Open "ICP Expert II" on Windows desktop.
- 8.1.4 Attach the drain pump tubing.
- 8.1.5 Attach the sample pump tubing.
- 8.1.6 Click "Pump Fast" to align the tubing. This should take approximately 5 to 10 seconds. Once aligned, click "Pump Off"
- 8.1.7 Lift the pressure bars and secure them with the pressure bar clamps.

TITLE: <u>Inductively Coupled Plasma – Optical Emissions Spectrometry</u> SDP NUMBER: <u>5318</u> **EFFECTIVE DATE: June 2011** PAGE: 6 13 8.1.8 Click "Plasma On". 8.1.9 Place the sipper wand in a bottle of FRESH Di water. Allow the instrument at least 20 minutes to warm-up. 8.1.10 8.2 Prepare the daily standards 8.2.1 Prepare an ICV according to SDP 5300. 8.2.2 Prepare a Calibration/Continuing Calibration Blank, (0.0) Standard/CCB, reagent blank for dilutions, and a rinse blank (they are the same) as follows, **Expiration: Prepared Daily** Align the Torch on the 1st and 15th of each month and as otherwise required. 8.3 The torch is aligned on the 1st and 15th of each month or the next available run date. Record on notes page of the "Metals by ICP" logbook. In addition, it must be run after any changes to the ICP have been made that may have resulted in a slight movement of torch placement. A wavelength calibration must be performed following a torch alignment. Note: Anything other than regular maintenance should be recorded in the instrument log. 8.3.1 Once the torch scan is completed, place the mouse (cross) on top of the peak and read the y-value (c/s) at the bottom of the instrument setup screen. Insure the peak of the torch align is greater than or equal to 30,000 intensity, if not contact the Lab Manager. 8.3.2 Store/Save results. 8.3.3 Keep the sipper wand in the diluted Varian Tuning solution for the next step. 8.4 Calibrate Detector and Wavelengths (if required) CAUTION: Never click "Calibrate Hardware" unless authorized to do so by a Varian Representative. Wavelength Calibrations must be performed after every torch align and may be used as a troubleshooting procedure.

Expert II."

The wavelength calibration program is found in the "Instrument" section of the "ICP

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- 8.5 Standardize the instrument using the 0.0 Standard (CCB) and the high standard.
 - 8.5.1 Center the H-bar on the peaks.
 - 8.5.1.1 For each element that has an H-bar on its graph, hold down the control key and left click on the H-bar (keep the left click held down) and drag the H-bar left or right to center the peak in between the bars. (May need to zoom in on peak to obtain best result)
 - 8.5.1.2 Once this is done for each element, click the "recalculate" button
- 8.6 Analyze Quality Control

Note: After each solution, clean the sipper wand with a kimwipe and place it in a bottle of fresh Di water.

- 8.6.1 Analyze the Mid-Point Standard (CCV) and the Initial Calibration Verification Standard (ICV).
 - 8.6.1.1 If the CCV and ICV are with-in limits, continue to the next step. If the CCV or ICV is out-of-limits, rerun it. If the rerun is out-of-limits, see the lab manager.
- 8.6.2 Analyze the Low-Level Continuing Calibration Verification Standard (LLCCV).
 - 8.6.2.1 If the LLCCV is with-in limits, continue to the next step. If the LLCCV is out-of-limits, rerun it. If the rerun is out-of-limits, see the lab manager.
- 8.6.3 Read the Continuing Calibration Blank (CCB).
 - 8.6.3.1 Report the exact results given. (Must read < LOQ).
- 8.7 Analyze Digestates

Note: In between each solution, clean the sipper wand with a kimwipe and place it in a bottle of fresh Di water or in a reagent blank if the sample had high concentrations of any element.

Note: After every microwave digested rack of samples, and at the end of analysis runs, analyze the CCV, LLCCV, and the CCB.

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	8.7.1	Analyze tl	he Method Bla	nk (MB) and Lab	oratory Cor	trol Sam	ple (LO	CS).
	8.7.2	read < LO limits – re	Q). If the LCS	port the exact ins is within limits of is now within library Lab Manager.	continue to	next step	. If it i	s out of
	8.7.3			LCS are within a as needed to kee				
	8.7.4	Analyze s	ample digestate	es, diluting as neo	cessary.			
		If dilution	s need to be ma	ade, proceed as fo	ollows			
		8.7.4.1	· •					
		8.7.4.2	See section 9	.2.4 for dilution c	alculation a	nd inforr	nation	
			8.7.4.2.1	Use reagent bla centrifuge tube				W
			8.7.4.2.2	Serial dilutions concentrations.	may be nee	ded for h	nigh	
		8.7.4.3	To run a dilut sample, but	tion, enter the san	nple informa	ation just	t like ar	ny other
			8.7.4.3.1	Type "Redil" be	efore the sar	nple nun	nber.	
			8.7.4.3.2	Change the Dil. dilution (i.e. if a needed, type "2	an additiona			
8.8	Run End	Standarda						
8.9			LCCV, and the	CCB				
0.7	8.9.1	•	ŕ	ide the acceptable	e limits ren	ın If sti	11 out o	f limits
	0.7.1	-	b Manager	rae ine acceptaor	C 111111111111111111111111111111111111	aii. 11 5ti	n out o	, ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,
8.10			nalysis Report.					
8.11		Instrument			_			
	8.11.1			ximately 10 minu	tes after con	npleting	analysis	S.
	8.11.2		Plasma Off"		_			
	8.11.3		ressure bar clar ube holders.	nps and lower pro	essure bars a	and remo	ove the	tubing

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	8.11.4		nimum of 10 and a maxim		s for the	system 1	to cool
		down. Ex	kit program an turn off chil	ler.			
8.12	2 Waste Disp	posal					
	8.12.1		ep wastes, sample digestate o another facility for dispos	•	nt waste >	> 0.2 mg	;/kg are
8.13	3 Maintaini	ing the instr	rument				
	8.13.1	Daily mai					
			Inspect torch.				
			Inspect pump tubing.				
		8.13.1.3	Check nebulizer.				
	8.13.2	Weekly m	naintenance (to be complete	ed on the 1st run	of the we	eek)	
		8.13.2.1	Clean torch.				
		8.13.2.2	Inspect snout.				
		8.13.2.3	Inspect bonnet.				
	8.13.3	Monthly 1	maintenance (to be complete	ted on the 1st rur	of the m	onth)	
		8.13.3.1	Clean spraychamber.				
		8.13.3.2					
			Inspect the state of the in-				
			Check the water level in				
		8.13.3.5	Clean the air filter behind	the chimney.			
	8.13.4	Bi-yearly	maintenance				
		8.13.4.1	Clean water particulate fi	lter on back of i	nstrumen	t.	
		8.13.4.2	Replace the water in recir	rculator and add	Chloram	ine-T.	
		8.13.4.3	Change argon filters.				
9.0 Data	a and Record	s Managem	ent:				
9.1	Reports/F	Records					
	9.1.1	•	ysis Report				
	9.1.2	Non-Rout	· · ·		,	. 1 .	C1 1:
	9.1.3		rt II (software) generated n	neasurement rep	ort is prii	ited and	filed in
	9.1.4		ate in a labeled folder. CP Logbook				

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	9.1.5 9.1.6 9.1.7	Purchased Reagents Logbook Metals Standard/Reagent Preparation Metals Digestion Preparation Log	Log				
9.2	Calculat	ions					
	9.2.1 Percent Difference (listed at the top of the Metals by ICP Logbook pages) The calculation is						
		Result of Standard Analysis – True Concent		on of Std	<u>.</u> X 100)	
	9.2.2	Mean and Relative Percent Difference	e (RPD), used for	or Duplic	ate An	alysis	
		$Mean = \underline{1st \ sample \ res}$	ult + duplicate S	Sample R	<u>Result</u>		
		Relative Percent Difference =	Higher Result - Mea		<u>lesult</u>	x 100	
	9.2.3	Theoretical Spike and % Recovery, us	sed for Spike A	nalysis			
Theoretical S	pike Conc	$eentration = \underline{ml \ spike \ solution \ used \ x \ spi} \\ sample \ wt \ (g)$	ike solution con	<u>centratio</u>	<u>n (μg/n</u>	<u>nl)</u>	
	F	Percent Recovery = spiked sample analyst theoretical spike co		<u>1</u>			
	9.2.4	Dilution Calculations (An excel spreadsheet has been created on the ICP 2 computer that performs the calculations for the analyst, after the analyst enters the requested information.)					
	7	What instrument is seeing = Result from Dilution Fa					
	1	New Dilution = What Instrument is seein Value of middle standard f	-	ement			

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		9.2.4.1	If new dilution is l	less than 10 r	ound to nea	rest who	ole num	ıber
		9.2.4.2	If new dilution is g	greater than 1	10 round to	a power	of ten	
9.3	Forms/Ma	nuals						
	9.3.1		als by ICP" logbook of standards and sam			nation re	elated to	the
		Sample I name	D - For samples, ent	ter sample nu	umber. For s	standard	s, enter	standard
		Dilution	(ml/wt) - Enter total	l dilution: vo	lume /samp	le weigh	ıt.	
		Inst read	ing (mg/kg) - Enter	the reading	from instrui	ment		
		Notes - For entries of receiver or sales profile number. For standards, the traceability number is entered.						
		correction recovery notes con to the dat page, alon and analy	ge - The left sided pass and clarifications, of spike analysis. The cerning analysis are a entry line to be dising with the sample not st initials. When dues section is reported	the mean and he logbook list required, a (scussed. This number, line applicate analy	nd RPD of dones are num (sequential) (number is on number, clarysis is performance)	uplicate bered. number entered or rificatio rmed, th	analysi When a is enter on the lon n notes e mean	is, and % additional red next eft sided , date, entered
	9.3.2		d of the analysis, the nent report is printed older.	-	,			date in a
	9.3.3		nt problems and reso in the Varian ICP In			nd servic	e calls	are

10.0 Training on SDP/Equipment

10.1 Training of analyst will be done in a timely manner. A new analyst will be under experienced analysts for at least one year unless otherwise approved by Lab Manager. An experienced analyst will demonstrate all correct procedures and techniques in the metals lab to a trainee prior to the new analyst working in the metals lab alone.

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- 10.2 Method blanks, laboratory control samples, duplicate and spiked samples, and standard reference materials will be analyzed to determine/gauge proficiency.
- 10.3 Once analyst is trained, no additional retraining is required unless a lapse in training occurs or if issues arise in an analyst's QA/QC, or sample data is observed.
- 11.0 User Responsibilities:

It is the responsibility of each user to insure that the instrument is operating properly and that all QA/QC procedures are followed.

12.0 User Performance Criteria:

Analyst will have a strong science background or previous lab experience prior to working in the metals lab. Typical experience is a 4 year science degree or >2 years lab experience.

- 13.0 Cross References:
 - 13.1 Techniques of Simultaneous ICP-OES 700-ES Series by Varian
 - 13.2 Veolia Environmental Services Metals By ICP Log
 - 13.3 SDP 5304 Analysis of Mercury by Direct Mercury Analyzer (DMA-80)
- 14.0 Regulatory/Permit Requirements:

All procedures must follow current and future federal or local requirements that are identified by the facility Waste Analysis Plan (WAP) that is incorporated into the Facility RCRA Part B permit.

- 15.0 Quality Control / Quality Assurance Procedures
 - 15.1 Primary Standardization is performed daily with the use of a calibration blank and a high standard, containing 5mg/kg arsenic, cadmium, chromium, and lead & 2mg/kg beryllium and mercury.
 - 15.2 Standardization is verified daily by analyzing the following calibration verification standards:
 - 15.2.1 (ICV) Initial Calibration Verification- Acceptable calibration standard preparation and the integrity of the calibration are verified by preparing and analyzing the daily ICV standard. This standard must be obtained from a source different from the calibration standards (2nd source).

Acceptance criteria: 90-110%

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15.2.2 Continuing calibration verification standards (CCV) are the middle standard used to verify the calibration of the instrument. It has the same concentration as the ICV but is made from the primary source. These standards are analyzed prior to the LLCCV standard analysis, prior to sample analysis, after every 10 samples, and at end of runs.

Acceptance criteria: 90-110%

15.2.3 Low level continuing calibration verification standard (LLCCV). This standard concentration is the lowest concentration standard used to verify the calibration of the instrument. The LLCCV is analyzed prior to sample analyses, after every 10 samples, and at the end of runs.

Acceptance criteria: 80-120%

15.2.4 Method blanks (MB) are analyzed to show that the analytical system is free of contamination. Analysis of an analyte free matrix to which all reagents used in processing the sample are added to show that they are free of contamination.

Acceptance criteria: <LOQ

15.2.5 Laboratory Control Samples (LCS) are analyzed to verify that the precision and bias of the analytical process are within control limits using a clean matrix. A standard reference material, obtained from a different source than the calibration standards, is microwave acid-digested with each batch of samples to be analyzed by ICP. The concentration may differ over time due to availability from vendor. The current LCS is kept in the metals laboratory hood. The certification of analysis is filed in the QC office. When a new material is purchased, the certified value +/- 20 percent is accepted until enough data is obtained to set a mean and acceptability limits.

Acceptance criteria: Within set limits

15.2.6 Duplicate analysis is performed for a minimum of every tenth sample in order to measure variability (precision)

Acceptance Criteria: <40 RPD (Relative Percent Difference)

15.2.7 Spike analysis is performed to measure the accuracy and appropriateness of the method. A third aliquot of the sample that is analyzed in duplicate is spiked with a known amount of multi-element standard from a different (2nd source) source than the calibration standards and analyzed after the original/duplicate pair.

Acceptance Criteria: 80-120% recovery.